

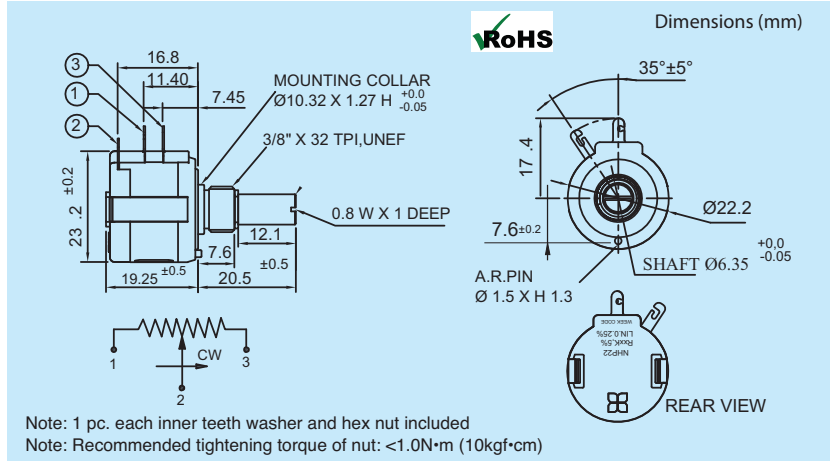
NHP22 Series

Multi-Turn Potentiometer (Wirewound)



Standard Model Nos.

NHP22-10 (10 turns)
NHP22-5 (5 turns)
NHP22-3 (3 turns)



General Specifications

Standard Resistance 100, 200, 500, 1k, 2k, 5k, 10k, 20k Ω

Resistance Tolerance: $\pm 5\%$

Independent Linearity Tolerance: $\frac{5\text{-turn}}{\pm 0.5\%}$ $\frac{10\text{-turn}}{\pm 0.25\%}$

Electrical Travel: $360^\circ \times n \pm 5^\circ$ (n: No. of turns)

End Resistance: 0.1% or 5 ohms (whichever is less)

Noise: Within 100 Ω E.N.R.

Dielectric Strength: 1 minute at 1000 VAC

Power Rating: 1.0W (3 & 5-turn)
2.0W (10-turn)

Insulation Resistance: Over 1000M Ω at 500V.D.C.

Housing: Engineered plastic

Shaft: Stainless steel

Terminals: Brass, gold plated

Mechanical Travel: $360^\circ \times n \begin{matrix} +30^\circ \\ -0^\circ \end{matrix}$ (n: No. of turns)

Stopper Strength: Approx. 45 N-cm (32 Oz. inch)

Rotational Life: 500,000 (5-turn)
1,000,000 (10-turn)

Starting Torque: Within 0.5 N-cm (0.708 Oz. inch)

Operating Temp.: $-40^\circ\text{C} \dots +125^\circ\text{C}$

Resist. Temperature Coefficient of Wire: $\pm 20\text{p.p.m./}^\circ\text{C}$

Vibration: 15G / 10Hz to 2,000Hz 12 hours

Shock: 50G / 11ms 18 times

Mass: Approx. 20g

Protection Grade: IP40 (IP65 optional)

Resolution Chart (%)

Resist. Value (Ω)	100	200	500	1k	2k	5k	10k	20k	50k	100k
NHP22-5	0.086	0.069	0.055	0.046	0.044	0.036	0.026	0.024	0.018	-
NHP22-10	0.05	0.044	0.035	0.029	0.023	0.025	0.02	0.019	0.013	0.009

Available Options (please contact us)

3 turn version. Multi-ganged (up to 10 gangs, housing length extended by 17mm per gang). High torque. Rear shaft (6mm dia. x 15mm length). Special shaft machining (flatted, pin hole, length, diameter, etc.). Sealed housing and o-ring shaft seal for IP65 protection grade (torque increases with addition of o-ring). Internal slipping clutch.

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Specifications subject to change without notice.
Users should verify device performance in their specific application.